DERWENT-ACC-NO: 2006-523334

DERWENT-WEEK: 200654

TITLE: Measuring the wall thickness of melting devices filled with a glass melt and having a wall with a layer of refractory material comprises irradiating radar waves into the wall on the outer side and further processing

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PRIORITY-DATA: 2004DE-10056393 (November 23, 2004)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE
DE 102004056393 A1	May 24, 2006	DE

APPLICATION-DATA:

PUB-NO	APPL-DESCRIPTOR	APPL-NO	APPL-DATE
DE102004056393A1	N/A	2004DE-10056393	November 23, 2004

INT-CL-CURRENT:

TYPE	IPC	DATE
CIPP	G01B15/02	20060101
CIPS	G01N22/00	20060101

ABSTRACTED-PUB-NO: DE 102004056393 A1

BASIC-ABSTRACT:

NOVELTY - Method for measuring the wall thickness of melting devices filled with a glass melt and having a wall with a layer of refractory material comprises irradiating radar waves into the wall on the outer side, measuring the radar waves reflected at dielectric transitions and measuring the wall thickness from the reflections corresponding to the running time of the wall inner side-glass melt transition.

USE - For measuring the wall thickness of melting devices filled with a glass melt.

ADVANTAGE - The method is simple and universal.

EQUIVALENT-ABSTRACTS:

CERAMICS AND GLASS

Preferred Features: The wall thickness of the refractory material is measured. The radar waves are radiated at a frequency of 0.5-2 GHz. The wall of the melting device is measured at different sites.

TITLE-TERMS: MEASURE WALL THICK MELT DEVICE FILLED GLASS LAYER REFRACTORY MATERIAL COMPRISE IRRADIATE RADAR WAVE OUTER SIDE PROCESS

DERWENT-CLASS: L01 S02

CPI-CODES: L01-C02;

EPI-CODES: S02-A05A1; S02-A05C1;

SECONDARY-ACC-NO:
CPI Secondary Accession Numbers: 2006-163835
Non-CPI Secondary Accession Numbers: 2006-419345